## **Supplementary Information**

## Solution-Processed Donor-Acceptor Polymer Nanowire Network Semiconductors for High-Performance Field-Effect Transistors

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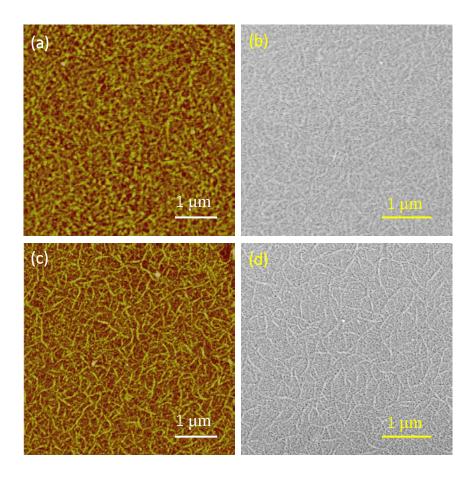
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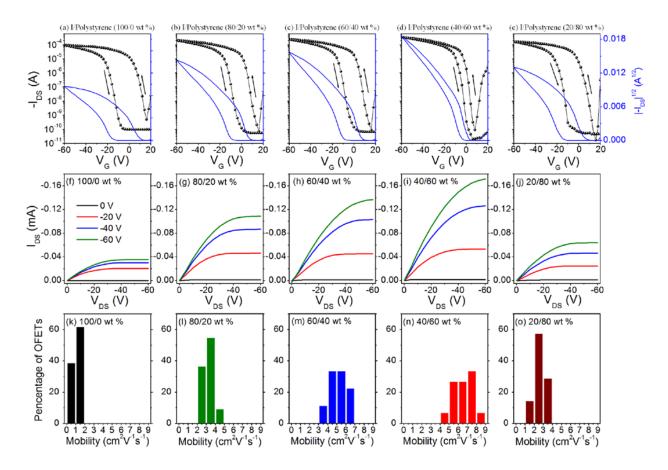
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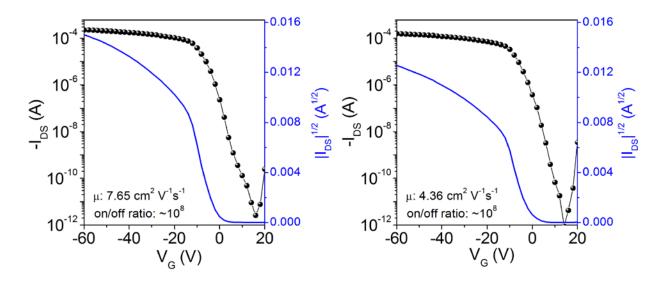
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**Figure S1.** AFM and SEM images of nanowire networks of (I) from (I)/polystyrene (40/60 wt %) films. (a) and (b) are AFM (topography) and SEM images of defused nanowire-like features of (I) from (I)/polystyrene film thermally annealed after polystyrene removal; (c) and (d) are AFM (topography, same as Figure 2f) and SEM images of well-defined nanowire network of (I) from thermally annealed (I)/polystyrene film with the polystyrene removed after thermal treatment.



**Figure S2.** Field-effect properties of OFETs with (I) and (I)/polystyrene channel semiconductors. Typical transfer characteristics of OFETs with (a) neat (I), and (b)-(e) (I)/polystyrene channel semiconductors with various polystyrene loadings; typical output curves of OFETs with (f) neat (I), and (g)-(j) (I)/polystyrene channel semiconductors with various polystyrene loadings; Mobility distributions of OFETs with (k) neat (I), and (l)-(o) (I)/polystyrene channel semiconductors with various polystyrene loadings.



**Figure S3.** Field-effect transistor performances based on annealed films with polystyrene removal. (a) Annealed with polystyrene; (b) annealed without polystyrene.